

## Supplementary Information for “Magnetotransport and magnetic properties of amorphous NdNi<sub>5</sub> thin films”

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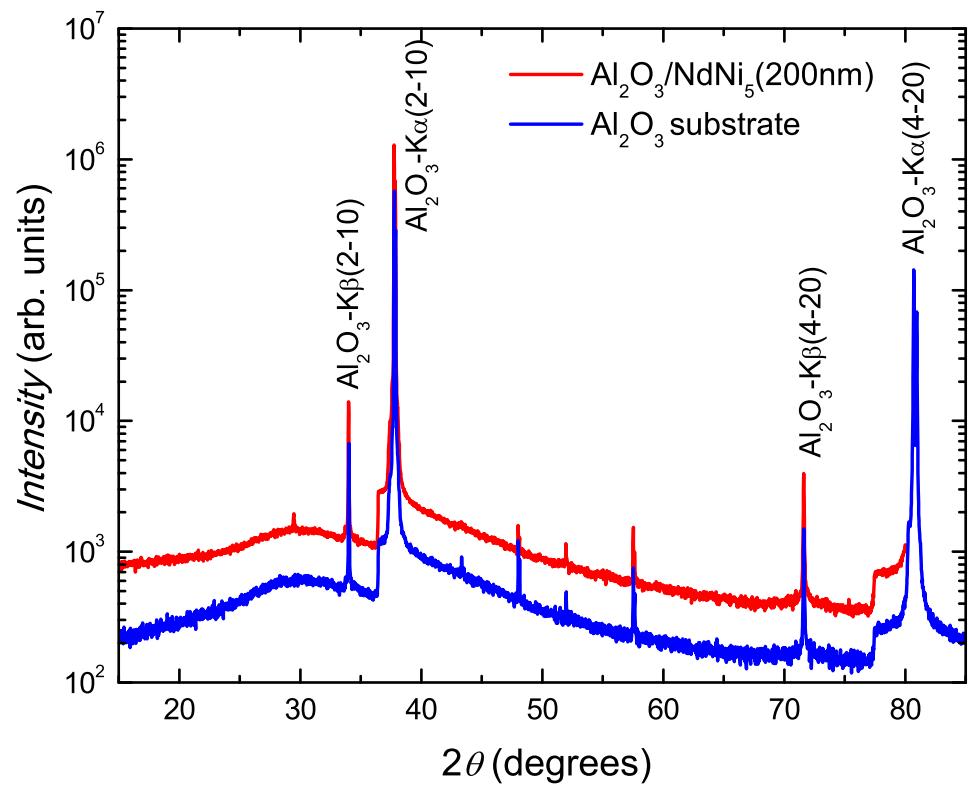
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**Fig. S1. Structural characterization.** High-angle X-ray diffraction data from a 200-nm-thick  $\text{NdNi}_5$  film deposited on  $\text{Al}_2\text{O}_3(1120)$  (red curve). The blue curve is the trace from the bare substrate.